# S-putty5-s



## **Thermal Conductive Putty**

LiPOLY S-putty5-s is a one-part dispensable material with thermal conductivity 10.0 W/m\*K. High deformation can fill small air gaps perfectly to remove tolerance. It also can overcome overflow and drying problems to increase the thermal conductivity. S-putty5-s is a great alternative to thermal grease and ideally suited for dispensing using the dispensing robot.

#### **■ FEATURES**

- / Thermal conductivity:10.0 W/m\*K / Bond line thickness:200-3000µm / Designed to remove manufacturing tolerances
- / Does not produce stress on delicate components
- / No vertical flow
- / Dispensable for serial manufacture
- / For any high compression and low stress application

### **■ TYPICAL APPLICATION**

- / Between CPU and heat sink
- / Between a component and heat sink
- / High speed mass storage drives
- / Telecommunication hardware
- / Flat-panel displays
- / Set-top box
- / IP CAM

#### **■ CONFIGURATIONS**

/ Cartridges: 30ml, 55ml, 330ml

/ Bucket: 1kg, 25kg

#### **■ PRESERVATION**

It can be preserved for 60 months under the condition of unopened and under room temperature 25°C.



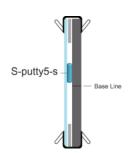
#### **■ TYPICAL PROPERTIES**

PROPERTY	S-putty5-s	TEST METHOD	UNIT
Color	Blue	Visual	-
Resin base	Silicone	-	-
Viscosity	20000	DIN 53018	Pa.s
Density	3.3	ASTM D792	g/cm³
Application temperature	-60~180	-	°C
Bond line thickness	200~3000	-	μm
Shelf life	60 months	-	-
ROHS & REACH	Compliant	-	-
ELECTRICAL			
Dielectric breakdown	12	ASTM D149	KV/mm
Volume resistivity	>1013	ASTM D257	Ohm-m
THERMAL	'		
Thermal conductivity	10.0	ASTM D5470	W/m*K
Thermal impedance@10psi	0.035	ASTM D5470	°C-in²/ W
Thermal impedance@30psi	0.031	ASTM D5470	°C-in²/ W
Thermal impedance@50psi	0.027	ASTM D5470	°C-in²/ W

#### **■ VERTICAL RELIABILITY**

Using 3.0mm pad as a gap control, put the putty between the aluminum and the glass panel mark the initial position. Then, p lace it in the oven with 125°C for 1,000 hours and observe its displacement after reliability test





Material no dropped or changed after high temperature aging testing